2858 #6 ID 7/18/02

TRANSMITTAL LETTER
(General - Patent Pending)

Docket No. P 6079.11005

In Re Application of: **Voorakaranam et al.**

Serial No.	Filing Date	Examiner	Group Art Unit
09/837,887	April 18, 2001		2858

Title: **METHOD AND APPARATUS FOR LOW COST SIGNATURE TESTING FOR ANALOG AND RF CIRCUITS**

TO THE COMMISSIONER OF PATENTS AND TRADEMARKS:

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Information Disclosure Citation w/references, Certificate of First Class Mail

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CERTIFICATE OF MAILING BY FIRST CLASS MAIL (37 CFR 1.8) Applicant(s): Voorakaranam et al			Docket No. P 6079.11005
Serial No. 09/837,887	Filing Date April 18, 2001	Examiner	Group Art Unit 2858

Invention: METHOD AND APPARATUS FOR LOW COST SIGNATURE TESTING FOR ANALOG AND RF CIRCUITS

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Docket Number (Optional)	Application Number
P 6079.11005	09/837,887
Applicant(s)	
Voorakaranam et al.	
Filing Date	**Group Art Unit**
April 18, 2001	2858

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		6,114,858	9/5/00	Kasten			

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation YES	Translation NO

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EXAMINER	DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

INFORMATION DISCLOSURE CITATION

Attorney Docket	Serial No.
P 6079.11005	09/837,887
Voorakaranam et al. et al.	
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